## Notice of References Cited Application/Control No. 10/607,689 Applicant(s)/Patent Under Reexamination MURAYAMA ET AL. Examiner Edwin A. León Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,176,538	01-1993	Hansell et al.	439/607
*	В	US-6,482,028	11-2002	Kumamoto et al.	439/498
*	С	US-5,085,596	02-1992	Bowen et al.	439/497
*	D	US-6,619,987	09-2003	Kumamoto et al.	439/610
*	E	US-6,685,511	02-2004	Akama et al.	439/610
*	F	US-6,478,624	11-2002	Ramey et al.	439/608
*	G	US-5,620,340	04-1997	Andrews, Derek	439/608
*	Н	US-3,587,028	06-1971	Uberbacher, Edward C.	439/49
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P					
	ø					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.